

<b>Form PTO-1449</b> <b>INFORMATION DISCLOSURE CITATION</b> <b>IN AN APPLICATION</b> <i>(Use several sheets if necessary)</i>	Docket Number 204552016501	Application Number NEW
	Applicant <b>Yuichi SATO</b>	
	Filing Date February 10, 2004	Group Art Unit
	Mailing Date February 10, 2004	

## U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
D Lee	1.	7/1998	5,780,899	Hu et al.			
	2.	11/1998	5,831,899	Wang et al.			
	3.	9/1999	5,960,289	Tsui et al.			
	4.	2/2000	6,020,222	Wollesen			

## FOREIGN PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO
D Lee	5.	3/1979	JP-A-54-037544	Japan			abs.
	6.	8/1986	JP-A-61-185972	Japan			abs.
	7.	1/1991	JP3022476	Japan			abs.
	8.	2/1992	JP-A-04-053090	Japan			abs.
	9.	6/1995	JP-A-07-161844	Japan			abs.
	10.	5/1996	JP-A-07-176633	Japan			abs.
	11.	8/1998	JP-A-10-222985	Japan			abs.

## OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title
	12.	"PRINCIPLES OF CMOS VLSI DESIGN", A Systems Perspective, Second Edition, , Neil H.E. Weste and Kamran Eshraghian, Chapter 10, pp 578-83, 1992
	13.	F. Assaderaghi et al., "Dynamic threshold-voltage MOSFET (DTMOS) for ultra-low voltage VLSI", IEEE Transactions on Electron Devices, vol. 44, no. 3, pp. 414-422, March 1997
	14.	Assaderaghi et al., 1994 "A dynamic threshold voltage MOSFET (DTMOS) for very low voltage operation" IEEE Electron Device Letters Vol. 15, pp 510-512.
	15.	Andoh et al., 1994 "Design methodology for low-voltage MOSFETS" IEEE International Electron Devices Meeting, Technical Digest, pp 79-82.
	16.	Assaderaghi et al., 1994 "A dynamic threshold voltage MOSFET (DTMOS) for ultra-low voltage operation" IEEE International Electron Devices Meeting, Technical Digest, pp 809-812.
	17.	David A. Hodges et al., "Analysis and design of digital integrated circuits", second edition, McGraw-Hill, Inc., PP 368-369; 1988

EXAMINER:

Douglas Little

1 DATE CONSIDERED:

4 Feb 05

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